SCAS688A - JUNE 2003 - REVISED JANUARY 2004

- 1.8-V Phase Lock Loop Clock Driver for **Double Data Rate (DDR II) Applications**
- Spread Spectrum Clock Compatible
- **Operating Frequency: 10 MHz to 400 MHz**
- Low Current Consumption: <135 mA
- Low Jitter (Cycle-Cycle): ±30 ps
- Low Output Skew: 35 ps
- Low Period Jitter: ±20 ps
- Low Dynamic Phase Offset:: ±15 ps
- Low Static Phase Offset:: ±50 ps
- **Distributes One Differential Clock Input to Ten Differential Outputs**
- 52-Ball μBGA (MicroStar Junior™ BGA, 0,65-mm pitch) and 40-Pin MLF

description

External Feedback Pins (FBIN, FBIN) are Used to Synchronize the Outputs to the Input Clocks

- Single-Ended Input and Single-Ended Output Modes
- Meets or Exceeds JESD82-8 PLL Standard for PC2-3200/4300
- **Fail-Safe Inputs**

The CDCU877 is a high-performance, low-jitter, low-skew, zero-delay buffer that distributes a differential clock input pair (CK, \overline{CK}) to ten differential pairs of clock outputs (Yn, \overline{Yn}) and to one differential pair of feedback clock outputs (FBOUT, FBOUT). The clock outputs are controlled by the input clocks (CK, CK), the feedback clocks (FBIN, FBIN), the LVCMOS control pins (OE, OS), and the analog power input (AV_{DD}). When OE is low, the clock outputs, except FBOUT/FBOUT, are disabled while the internal PLL continues to maintain its locked-in frequency. OS (output select) is a program pin that must be tied to GND or V_{DD}. When OS is high, OE functions as previously described. When OS and OE are both low, OE has no affect on Y7/Y7, they are free running. When AVDD is grounded, the PLL is turned off and bypassed for test purposes.

When both clock inputs (CK, CK) are logic low, the device enters in a low power mode. An input logic detection circuit on the differential inputs, independent from input buffers, detects the logic low level and performs in a low power state where all outputs, the feedback, and the PLL are off. When the clock inputs transition from being logic low to being differential signals, the PLL turns back on, the inputs and the outputs are enabled, and the PLL obtains phase lock between the feedback clock pair (FBIN, FBIN) and the clock input pair (CK, CK) within the specified stabilization time.

The CDCU877 is able to track spread spectrum clocking (SSC) for reduced EMI. This device operates from -40°C to 85°C.

AVAILABLE OPTIONS							
Τ _Α	52-Ball BGA	40-Pin MLF					
–40°C to 85°C	CDCU877ZQL (Pb-Free)	CDCU877RTB					
–40°C to 85°C	CDCU877AZQL (Pb-Free)	CDCU877ARTB					
-40°C to 85°C	CDCU877GQL						
–40°C to 85°C	CDCU877AGQL						



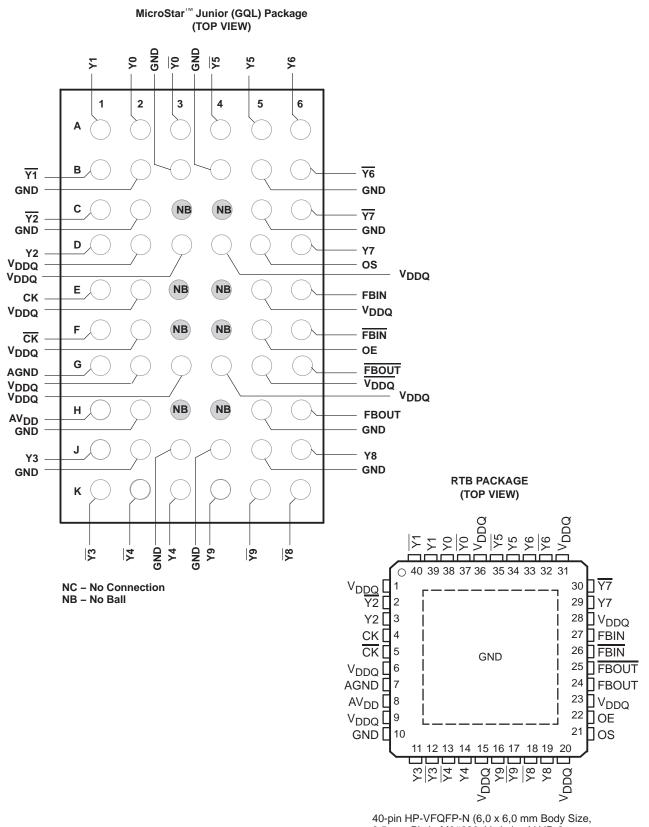
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

MicroStar Junior is a trademark of Texas Instruments

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SCAS688A – JUNE 2003 – REVISED JANUARY 2004



0,5 mm Pitch, M0#220, Variation VJJD-2, E2 = D2 = 2,9 mm \pm 0,15 mm) Package Pinouts



SCAS688A - JUNE 2003 - REVISED JANUARY 2004

NAME	BGA	MLF	I/O	DESCRIPTION
AGND	G1	7		Analog ground
AV _{DD}	H1	8		Analog power
CK	E1	4	Ι	Clock input with a (10 k Ω to 100 k Ω) pulldown resistor
CK	F1	5	I	Complementary clock input with a (10 k Ω to 100 k Ω) pulldown resistor
FBIN	E6	27	I	Feedback clock input
FBIN	F6	26	I	Complementary feedback clock input
FBOUT	H6	24	0	Feedback clock output
FBOUT	G6	25	0	Complementary feedback clock output
OE	F5	22	I	Output enable (asynchronous)
OS	D5	21	I	Output select (tied to GND or V _{DD})
GND	B2, B3, B4, B5, C2, C5, H2, H5, J2, J3, J4, J5	10		Ground
V _{DDQ}	D2, D3, D4, E2, E5, F2, G2, G3, G4, G5	1, 6, 9, 15, 20, 23, 28, 31, 36		Logic and output power
Y[0:9]	A2, A1, D1, J1, K3, A5, A6, D6, J6, K4	38, 39, 3, 11, 14, 34, 33, 29, 19, 16	0	Clock outputs
Y[0:9]	A3, B1, C1, K1, K2, A4, B6, C6, K6, K5	37, 40, 2, 12, 13, 35, 32, 30, 18, 17	0	Complementary clock outputs

Table 1. Terminal Functions

Table 2. Function Table

		INPUTS				PLL			
AV _{DD}	OE	OS	СК	СК	Y	Y	FBOUT	FBOUT	
GND	Н	Х	L	Н	L	н	L	Н	Bypassed/ Off
GND	Н	Х	н	L	н	L	Н	L	Bypassed/ Off
GND	L	н	L	Н	LZ	LZ	L	Н	Bypassed/ Off
GND	L	L	н	L	LZ Y7 Active	LZ Y7 Active	Н	L	Bypassed/ Off
1.8 V Nominal	L	Н	L	Н	LZ	LZ	L	н	On
1.8 V Nominal	L	L	н	L	LZ Y7 Active	LZ Y7 Active	Н	L	On
1.8 V Nominal	Н	Х	L	Н	L	Н	L	Н	On
1.8 V Nominal	Н	Х	Н	L	Н	L	Н	L	On
1.8 V Nominal	Х	Х	L	L	LZ	LZ	LZ	LZ	Off
Х	Х	Х	Н	Н		•	Reserved	•	-



SCAS688A - JUNE 2003 - REVISED JANUARY 2004

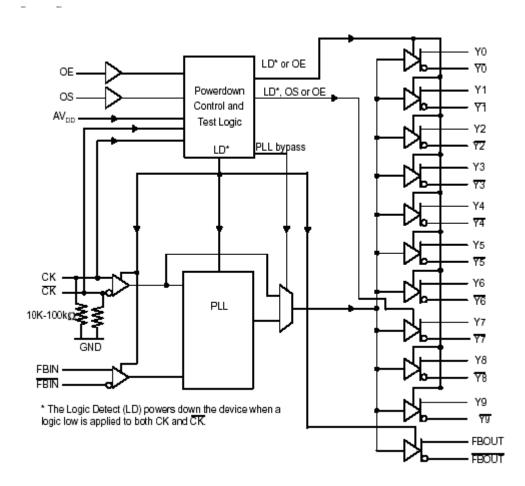


Figure 1. Logic Diagram (Positive Logic)



SCAS688A - JUNE 2003 - REVISED JANUARY 2004

absolute maximum ratings over operating free-air temperature (unless otherwise noted)[†]

Supply voltage range, V _{DDQ} or AV _{DD}	–0.5 V to 2.5 V
Input voltage range, V _I (see Notes 1 and 2)	–0.5 V to V _{DDQ} + 0.5 V
Output voltage range, V _O (see Notes 1 and 2)	–0.5 V to V _{DDQ} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{DDQ}$)	±50 mA
Output clamp voltage, I_{OK} (V _O < 0 or V _O > V _{DDQ})	±50 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{DDQ})$	±50 mA
Continuous current through each V _{DDQ} or GND	±100 mA
Storage temperature range, T _{STG}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed

2. This value is limited to 2.5 V maximum.

recommended operating conditions

			MIN	NOM	MAX	UNIT
VDDQ	Q Output supply voltage		1.7	1.8	1.9	V
AVDD	Supply voltage	See Note 1		VDDQ		
VIL	Low-level input voltage (see Note 2)	OE, OS			$0.35 \times V_{DDQ}$	V
VIH	High-level input voltage (see Note 2)	CK, CK	$0.65 \times V_{DDQ}$			V
IOH	High-level output current (see Figure 2	2)			-9	mA
IOL	Low-level output current (see Figure 2	2)			9	mA
V_{IX}	Input differential-pair cross voltage		(V _{DDQ} /2)-0.15		(V _{DDQ} /2)+0.15	V
\vee_{I}	Input voltage level		-0.3		V _{DDQ} +0.3	V
VID	Input differential voltage	DC	0.3		V _{DDQ} +0.4	V
	(see Note 2 and Figure 9)	AC	0.6		V _{DDQ} +0.4	V
Т _А	Operating free-air temperature		-40		85	°C

NOTES: 1. The PLL is turned off and bypassed for test purposes when AV_{DD} is grounded. During this test mode, V_{DDQ} remains within the recommended operating conditions and no timing parameters are ensured.

2. V_{ID} is the magnitude of the difference between the input level on CK and the input level on CK, see Figure 9 for definition. The CK and CK V_{IH} and V_{IL} limits define the dc low and high levels for the logic detect state.



SCAS688A - JUNE 2003 - REVISED JANUARY 2004

electrical characteristics over recommended operating free-air temperature range

PARAMETER		TEST CONDITIONS	AV _{DD} , V _{DDQ}	MIN	TYP	МАХ	UNIT			
VIK	Input (cl inputs)		lj = 18 mA	1.7 V			-1.2	V		
Vон			High-level output voltage $I_{OH} = -100 \mu A$		I _{OH} = -100 μA	1.7 V to 1.9 V	V _{DDQ} - 0.2			V
0			$I_{OH} = -9 \text{ mA}$	1.7 V	1.1					
	Level and a devidence to a literate		I _{OL} = 100 μA				0.1			
VOL	Low-level output voltage		I _{OL} = 9 mA	1.7 V			0.6	V		
IO(DL)	Low-level output current, disa	abled	$V_{O(DL)} = 100 \text{ mV}, \text{ OE} = L$	1.7 V	100			μA		
VOD	Differential output voltage (see Note 1)			1.7 V	0.5			V		
	Input current	CK, CK		1.9 V		<u>+2</u>	±250	μΑ		
l		OE, O <u>S,</u> FBIN, FBIN		1.9 V			±10			
IDD(LD)	Supply current, static (IDDQ	+ I _{ADD})	CK and $\overline{CK} = L$	1.9 V			500	μA		
IDD	Supply current, dynamic (IDDO + IADD)		CK and CK = 270 MHz, All outputs are open (not connected to a PCB)	1.9 V			135	mA		
.00	(see Note 2 for CPD calculat	ion)	All outputs are loaded with 2 pF and 120- Ω termination resistor	1.9 V			235			
-		CK, CK	V _I = V _{DD} or GND	1.8 V	2		3	-		
Cl	Input capacitance	FBIN, FBIN	V _I = V _{DD} or GND	1.8 V	2		3	pF		
-		CK, CK	$V_{I} = V_{DD}$ or GND	1.8 V			0.25			
$C_{I(\Delta)}$	Change in input current	FBIN, FBIN	$V_{I} = V_{DD}$ or GND	1.8 V			0.25	pF		

NOTES: 1. V_{OD} is the magnitude of the difference between the true and complimentary outputs. See Figure 9 for a definition.

Total IDD = IDDQ + IADD = fCK × CPD × VDDQ, solving for CPD = (IDDQ + IADD)/(fCK × VDDQ) where fCK is the input frequency, VDDQ is the power supply, and CPD is the power dissipation capacitance.

timing requirements over recommended operating free-air temperature range

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
fCK	Clock frequency (operating, see Notes 1 and 2)	AV _{DD} , V _{DD} = 1.8 V ±0.1 V	10	400) MHz
fCK	Clock frequency (application, see Notes 1 and 3)	AV _{DD} , V _{DD} = 1.8 V ±0.1 V	160	340) MHz
^t DC	Duty cycle, input clock	AV _{DD} , V _{DD} = 1.8 V ±0.1 V	40%	60%)
tL	Stabilization time (see Note 4)	AV _{DD} , V _{DD} = 1.8 V ±0.1 V		1:	2 μs

NOTES: 1. The PLL must be able to handle spread spectrum induced skew.

2. Operating clock frequency indicates a range over which the PLL must be able to lock, but in which it is not required to meet the other timing parameters (used for low speed system debug).

3. Application clock frequency indicates a range over which the PLL must meet all timing parameters.

4. Stabilization time is the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal after power up. During normal operation, the stabilization time is also the time required for the integrated PLL circuit to obtain phase lock of its feedback signal to its reference signal when CK and CK go to a logic low state, enter the power-down mode and later return to active operation. CK and CK may be left floating after they have been driven low for one complete clock cycle.



SCAS688A – JUNE 2003 – REVISED JANUARY 2004

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Note 1)

 $AV_{DD}, V_{DD} = 1.8 \text{ V} \pm 0.1 \text{ V}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
ten	Enable time, OE to any Y/\overline{Y}	See Figure 11			8	ns	
^t dis	Disable time, OE to any Y/\overline{Y}	See Figure 11			8	ns	
^t jit(cc+)			0		40		
tjit(cc-)	Cycle-to-cycle period jitter (see Note 8)	160 MHz to 190 MHz, see Figure 4	0		-40	ps	
tjit(cc+)			0		30		
tjit(cc-)	Cycle-to-cycle period jitter (see Note 8)	190 MHz to 340 MHz, see Figure 4	0		-30	ps	
t _(φ)	Static phase offset time (see Note 2)	See Figure 5	-50		50	ps	
t(φ)dyn	Dynamic phase offset time	See Figure 10	-15		15	ps	
^t sk(o)	Output clock skew	See Figure 6			35	ps	
		160 MHz to 190 MHz, see Figure 7	-30		30	ps	
^t jit(per)	Period jitter (see Notes 3 and 8)	190 MHz to 340 MHz, see Figure 7	-20		20	ps	
	Half-period jitter (see Notes 3 and 8)	160 MHz to 190 MHz, see Figure 8	-115		115	ps	
		190 MHz to 250 MHz, see Figure 8	-70		70	ps	
^t jit(hper)		250 MHz to 300 MHz, see Figure 8	-40		40	ps	
		300 MHz to 340 MHz, see Figure 8	-60		60	ps	
	Slew rate, OE	See Figure 3 and Figure 9	0.5			V/ns	
SR	Input clock skew rate	See Figure 3 and Figure 9	1	2.5	4	V/ns	
SK	Output clock slew rate (see Notes 4 and 5)	See Figure 3 and Figure 9	1.5	2.5	3	V/ns	
	Output differential-pair cross voltage	See Figure 2, CDCU877	(V _{DDQ} /2) - 0.1		(V _{DDQ} /2) + 0.1		
VOX	(see Note 6)	See Figure 2, CDCU877A (see Note 7) (0-85°C)	(V _{DDQ} /2) - 0.1		(V _{DDQ} /2) + 0.1	V	
	SSC modulation frequency		30		33	kHz	
	SSC clock input frequency deviation		0%		-0.5%		
	PLL loop bandwidth		2			MHz	

NOTES: 1. There are two different terminations that are used with the following tests. The load/board in Figure 2 is used to measure the input and output differential-pair cross voltage only. The load/board in Figure 3 is used to measure all other tests. For consistency, equal length cables must be used.

- 2. Phase static offset time does not include jitter.
- 3. Period jitter, half-period jitter specifications are separate specifications that must be met independently of each other.
- 4. The output slew rate is determined from the IBIS model into the load shown in Figure 3.
- 5. To eliminate the impact of input slew rates on static phase offset, the input skew rates of reference clock input CK and CK and feedback clock inputs FBIN and FBIN are recommended to be nearly equal. The 2.5-V/ns skew rates are shown as a recommended target. Compliance with these typical values is not mandatory if it can adequately shown that alternative characteristics meet the requirements of the registered DDR2 DIMM application.
- 6. Output differential-pair cross voltage specified at the DRAM clock input or the test load.
- 7. VOX of CDCU877A is on average 30 mV lower than that of CDCU877 for the same application.
- 8. This parameter is assured by design and characterization.



SCAS688A - JUNE 2003 - REVISED JANUARY 2004

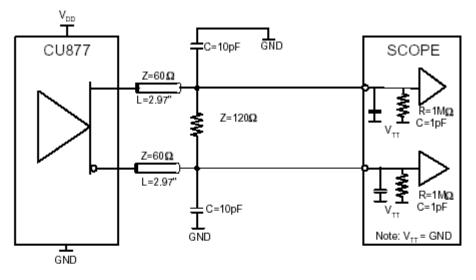


Figure 2. Output Load Test Circuit 1

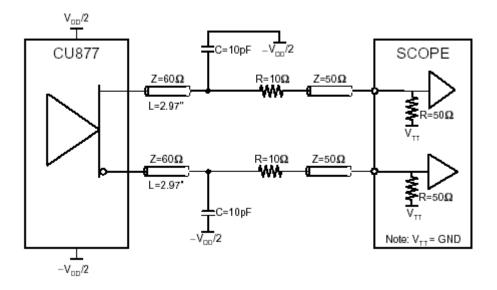
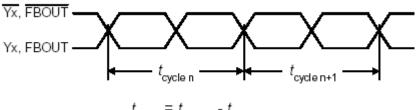
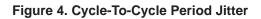


Figure 3. Output Load Test Circuit 2

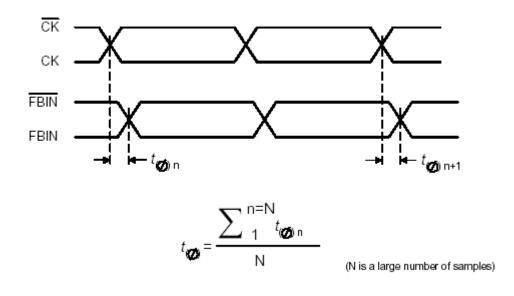


 $t_{jit(cc)} = t_{cycle n} - t_{cycle n+1}$



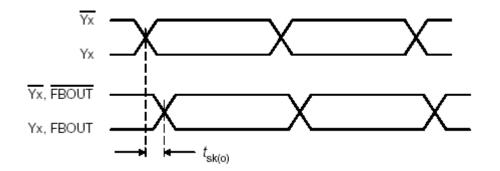


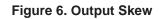
SCAS688A - JUNE 2003 - REVISED JANUARY 2004



(N>1000 samples)

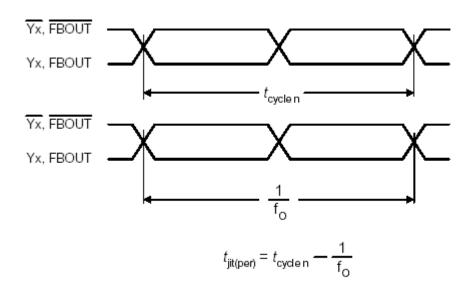






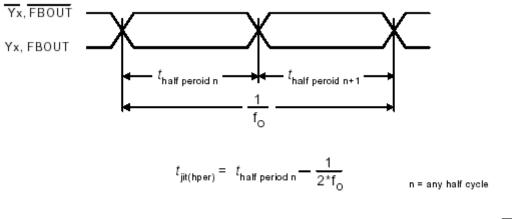


SCAS688A - JUNE 2003 - REVISED JANUARY 2004



 $(f_0 = average input frequency measured at CK/\overline{CK})$

Figure 7. Period Jitter



 $(f_O = average input frequency measured at CK/\overline{CK})$





SCAS688A - JUNE 2003 - REVISED JANUARY 2004

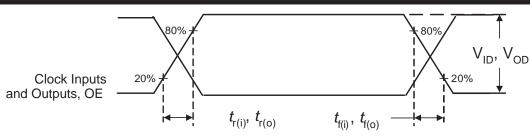




Figure 9. Input and Output Slew Rates

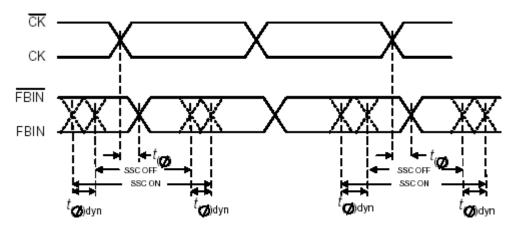


Figure 10. Dynamic Phase Offset

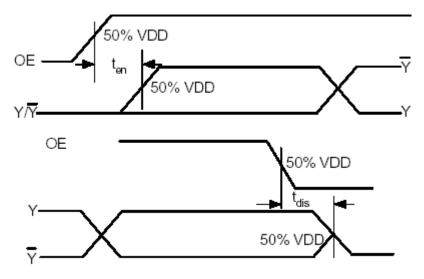
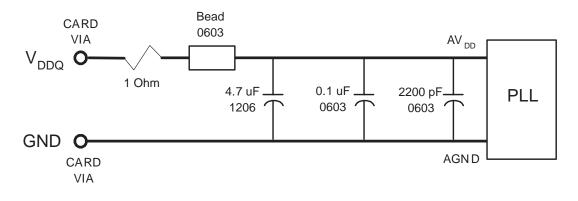


Figure 11. Time Delay Between OE and Clock Output (Y, \overline{Y})



SCAS688A - JUNE 2003 - REVISED JANUARY 2004

RECOMMENDED AVDD FILTERING



See Notes 9, 10, and 11

Figure 12. Recommended $\mathrm{AV}_{\mathrm{DD}}$ Filtering

- NOTES: 9. Place the 2200-pF capacitor close to the PLL.
 - 10. Use a wide trace for the PLL analog power and ground. Connect PLL and capacitors to AGND trace and connect trace to one GND via (farthest from the PLL).
 - 11. Recommended bead: Fair-Rite PN 2506036017Y0 or equilvalent (0.8 Ω dc maximum, 600 Ω at 100 MHz).

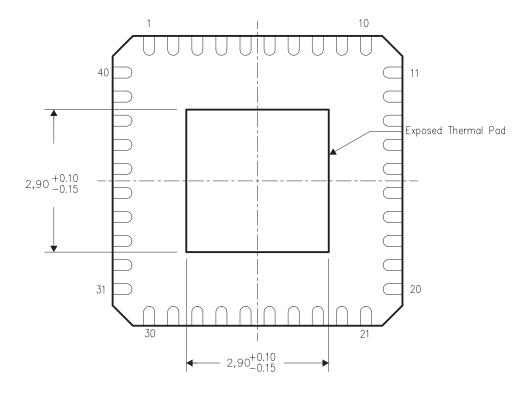


THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB), the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to a ground plane or special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No-Lead Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.





NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
CDCU877AGQLR	ACTIVE	VFBGA	GQL	52	1000	None	Call TI	Level-3-235C-168 HR
CDCU877AGQLT	ACTIVE	VFBGA	GQL	52	250	None	Call TI	Level-3-235C-168 HR
CDCU877ARTBR	ACTIVE	QFN	RTB	40	2500	None	CU SNPB	Level-3-235C-168 HR
CDCU877ARTBT	ACTIVE	QFN	RTB	40	250	None	CU SNPB	Level-3-235C-168 HR
CDCU877AZQLR	ACTIVE	VFBGA	ZQL	52	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR
CDCU877AZQLT	ACTIVE	VFBGA	ZQL	52	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR
CDCU877GQLR	ACTIVE	VFBGA	GQL	52	1000	None	Call TI	Level-3-235C-168 HR
CDCU877GQLT	ACTIVE	VFBGA	GQL	52	250	None	Call TI	Level-3-235C-168 HR
CDCU877RTBR	ACTIVE	QFN	RTB	40	2500	None	CU SNPB	Level-3-235C-168 HR
CDCU877RTBT	ACTIVE	QFN	RTB	40	250	None	CU SNPB	Level-3-235C-168 HR
CDCU877ZQLR	ACTIVE	VFBGA	ZQL	52	1000	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR
CDCU877ZQLT	ACTIVE	VFBGA	ZQL	52	250	Green (RoHS & no Sb/Br)	SNAGCU	Level-2-260C-1 YEAR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - May not be currently available - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

None: Not yet available Lead (Pb-Free).

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.

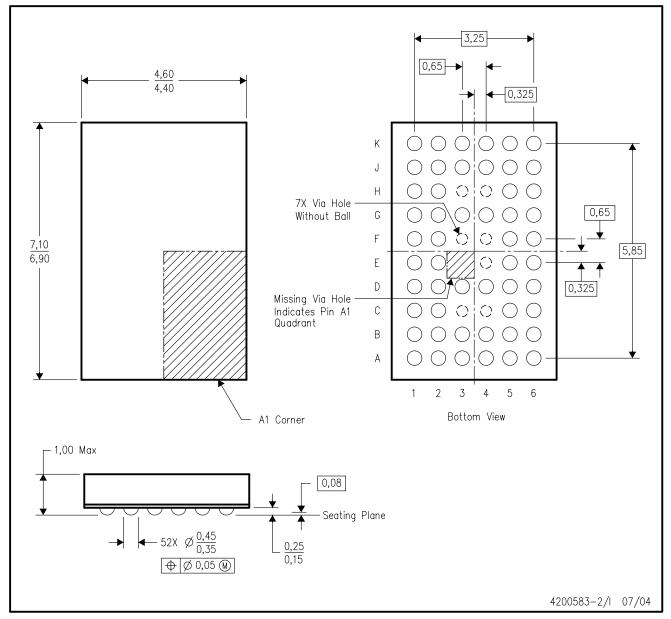
⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDECindustry standard classifications, and peak solder temperature.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

GQL (R-PBGA-N52)

PLASTIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

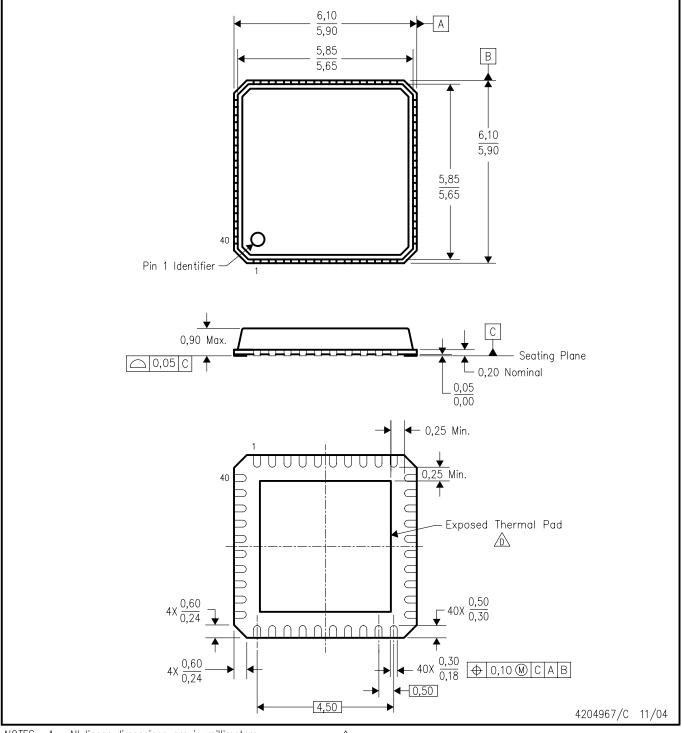
C. Falls within JEDEC MO-225 variation BA.

D. This package is tin-lead (SnPb). Refer to the 52 ZQL package (drawing 4204437) for lead-free.



RTB (S-PQFP-N40)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994. B. This drawing is subject to change without notice.

The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.

C. QFN (Quad Flatpack No-Lead) Package configuration.



 Δ

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Amplifiers	amplifier.ti.com	Audio	www.ti.com/audio
Data Converters	dataconverter.ti.com	Automotive	www.ti.com/automotive
DSP	dsp.ti.com	Broadband	www.ti.com/broadband
Interface	interface.ti.com	Digital Control	www.ti.com/digitalcontrol
Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
		Telephony	www.ti.com/telephony
		Video & Imaging	www.ti.com/video
		Wireless	www.ti.com/wireless

Mailing Address:

Texas Instruments

Post Office Box 655303 Dallas, Texas 75265

Copyright © 2005, Texas Instruments Incorporated